

September 1997

### Features

- Cascadable
- Fanout (Over Temperature Range)
  - Standard Outputs ..... 10 LSTTL Loads
  - Bus Driver Outputs ..... 15 LSTTL Loads
- Wide Operating Temperature Range ... -55°C to 125°C
- Balanced Propagation Delay and Transition Times
- Significant Power Reduction Compared to LSTTL Logic ICs
- HC Types
  - 2V to 6V Operation
  - High Noise Immunity:  $N_{IL} = 30\%$ ,  $N_{IH} = 30\%$  of  $V_{CC}$  at  $V_{CC} = 5V$
- HCT Types
  - 4.5V to 5.5V Operation
  - Direct LSTTL Input Logic Compatibility,  $V_{IL} = 0.8V$  (Max),  $V_{IH} = 2V$  (Min)
  - CMOS Input Compatibility,  $I_l \leq 1\mu A$  at  $V_{OL}, V_{OH}$

### Description

The Harris CD74HC688 and CD74HCT688 are 8-bit magnitude comparators designed for use in computer and logic applications that require the comparison of two 8-bit binary words. When the compared words are equal the output (Y) is low and can be used as the enabling input for the next device in a cascaded application.

### Ordering Information

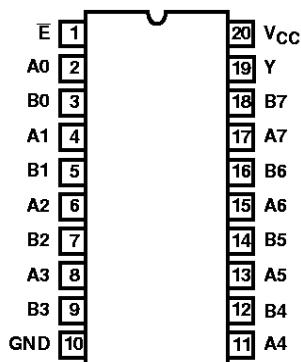
PART NUMBER	TEMP. RANGE (°C)	PACKAGE	PKG. NO.
CD74HC688E	-55 to 125	20 Ld PDIP	E20.3
CD74HCT688E	-55 to 125	20 Ld PDIP	E20.3
CD74HC688M	-55 to 125	20 Ld SOIC	M20.3
CD74HCT688M	-55 to 125	20 Ld SOIC	M20.3
CD54HC688	-55 to 125	Wafer	

#### NOTES:

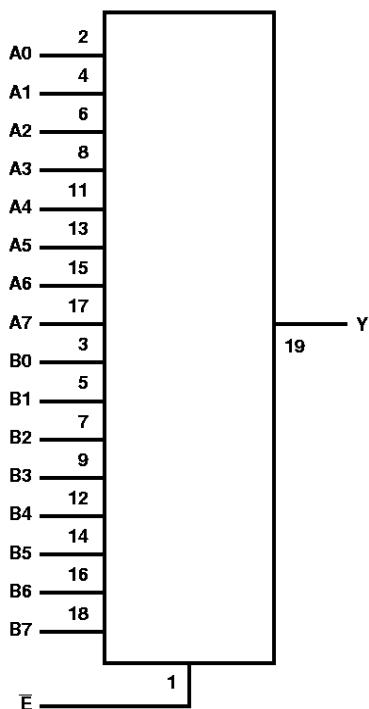
1. When ordering, use the entire part number. Add the suffix 96 to obtain the variant in the tape and reel.
2. Die for this part number is available which meets all electrical specifications. Please contact your local sales office or Harris customer service for ordering information.

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### Pinout

 CD74HC688, CD74HCT688  
 (PDIP, SOIC)  
 TOP VIEW


***Functional Diagram***

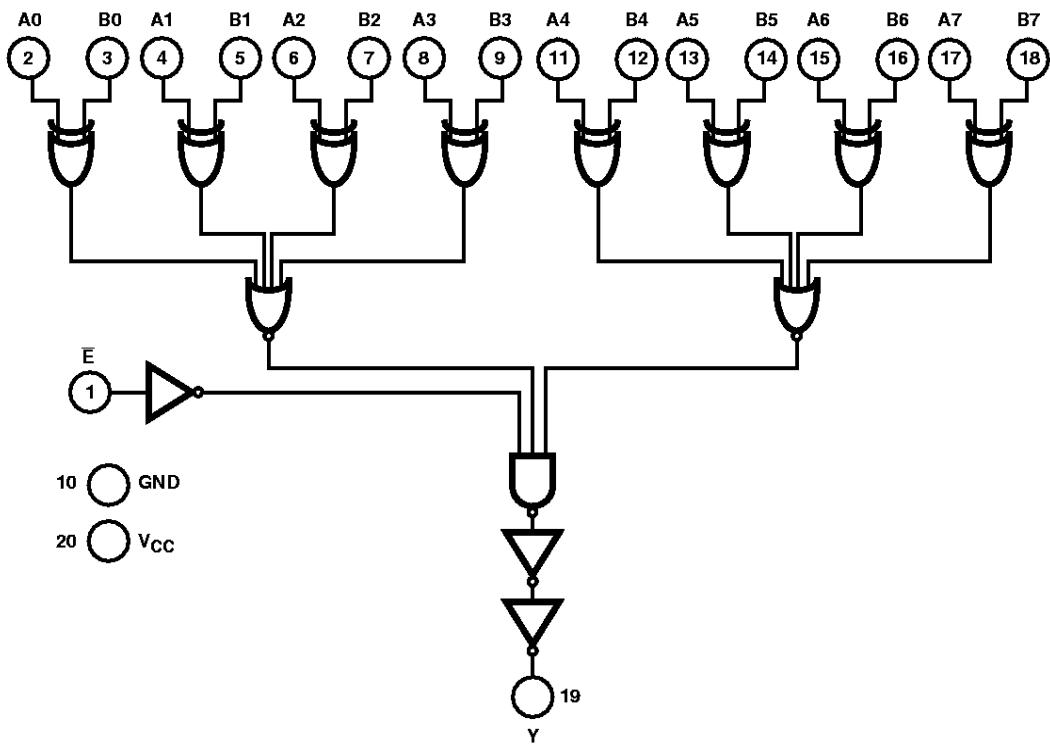


**TRUTH TABLE**

INPUTS		OUPUTS
A, B	$\bar{E}$	Y
A = B	L	L
A $\neq$ B	L	H
X	H	H

NOTES: H = High Voltage Level, L = Low Voltage Level, X = Don't Care

*Logic Diagram*



# CD74HC688, CD74HCT688

## Absolute Maximum Ratings

DC Supply Voltage, V <sub>CC</sub>	-0.5V to 7V
DC Input Diode Current, I <sub>IK</sub>	
For V <sub>I</sub> < -0.5V or V <sub>I</sub> > V <sub>CC</sub> + 0.5V	±20mA
DC Output Diode Current, I <sub>OK</sub>	
For V <sub>O</sub> < -0.5V or V <sub>O</sub> > V <sub>CC</sub> + 0.5V	±20mA
DC Output Source or Sink Current per Output Pin, I <sub>O</sub>	
For V <sub>O</sub> > -0.5V or V <sub>O</sub> < V <sub>CC</sub> + 0.5V	±25mA
DC V <sub>CC</sub> or Ground Current, I <sub>CC</sub> or I <sub>GND</sub>	±50mA

## Thermal Information

Thermal Resistance (Typical, Note 3)	θ <sub>JA</sub> (°C/W)
PDIP Package	125
SOIC Package	100
Maximum Junction Temperature	150°C
Maximum Storage Temperature Range	-65°C to 150°C
Maximum Lead Temperature (Soldering 10s)	300°C (SOIC - Lead Tips Only)

## Operating Conditions

Temperature Range (T <sub>A</sub> )	-55°C to 125°C
Supply Voltage Range, V <sub>CC</sub>	
HC Types	2V to 6V
HCT Types	4.5V to 5.5V
DC Input or Output Voltage, V <sub>I</sub> , V <sub>O</sub>	0V to V <sub>CC</sub>
Input Rise and Fall Time	
2V	1000ns (Max)
4.5V	500ns (Max)
6V	400ns (Max)

**CAUTION:** Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

### NOTE:

3. θ<sub>JA</sub> is measured with the component mounted on an evaluation PC board in free air.

## DC Electrical Specifications

PARAMETER	SYMBOL	TEST CONDITIONS		V <sub>CC</sub> (V)	25°C			-40°C TO 85°C		-55°C TO 125°C		UNITS	
		V <sub>I</sub> (V)	I <sub>O</sub> (mA)		MIN	TYP	MAX	MIN	MAX	MIN	MAX		
<b>HC TYPES</b>													
High Level Input Voltage	V <sub>IH</sub>	-	-	2	1.5	-	-	1.5	-	1.5	-	V	
				4.5	3.15	-	-	3.15	-	3.15	-	V	
				6	4.2	-	-	4.2	-	4.2	-	V	
Low Level Input Voltage	V <sub>IL</sub>	-	-	2	-	-	0.5	-	0.5	-	0.5	V	
				4.5	-	-	1.35	-	1.35	-	1.35	V	
				6	-	-	1.8	-	1.8	-	1.8	V	
High Level Output Voltage CMOS Loads	V <sub>OH</sub>	V <sub>IH</sub> or V <sub>IL</sub>	-0.02	2	1.9	-	-	1.9	-	1.9	-	V	
			-0.02	4.5	4.4	-	-	4.4	-	4.4	-	V	
			-0.02	6	5.9	-	-	5.9	-	5.9	-	V	
High Level Output Voltage TTL Loads			-	-	-	-	-	-	-	-	-	V	
			-4	4.5	3.98	-	-	3.84	-	3.7	-	V	
			-5.2	6	5.48	-	-	5.34	-	5.2	-	V	
Low Level Output Voltage CMOS Loads	V <sub>OL</sub>	V <sub>IH</sub> or V <sub>IL</sub>	0.02	2	-	-	0.1	-	0.1	-	0.1	V	
			0.02	4.5	-	-	0.1	-	0.1	-	0.1	V	
			0.02	6	-	-	0.1	-	0.1	-	0.1	V	
Low Level Output Voltage TTL Loads			-	-	-	-	-	-	-	-	-	V	
			4	4.5	-	-	0.26	-	0.33	-	0.4	V	
			5.2	6	-	-	0.26	-	0.33	-	0.4	V	
Input Leakage Current	I <sub>I</sub>	V <sub>CC</sub> or GND	-	6	-	-	±0.1	-	±1	-	±1	µA	
Quiescent Device Current	I <sub>CC</sub>	V <sub>CC</sub> or GND	0	6	-	-	8	-	80	-	160	µA	

# CD74HC688, CD74HCT688

## DC Electrical Specifications (Continued)

PARAMETER	SYMBOL	TEST CONDITIONS		V <sub>CC</sub> (V)	25°C			-40°C TO 85°C		-55°C TO 125°C		UNITS
		V <sub>I</sub> (V)	I <sub>O</sub> (mA)		MIN	TYP	MAX	MIN	MAX	MIN	MAX	
<b>HCT TYPES</b>												
High Level Input Voltage	V <sub>IH</sub>	-	-	4.5 to 5.5	2	-	-	2	-	2	-	V
Low Level Input Voltage	V <sub>IL</sub>	-	-	4.5 to 5.5	-	-	0.8	-	0.8	-	0.8	V
High Level Output Voltage CMOS Loads	V <sub>OH</sub>	V <sub>IH</sub> or V <sub>IL</sub>	-0.02	4.5	4.4	-	-	4.4	-	4.4	-	V
High Level Output Voltage TTL Loads			-4	4.5	3.98	-	-	3.84	-	3.7	-	V
Low Level Output Voltage CMOS Loads	V <sub>OL</sub>	V <sub>IH</sub> or V <sub>IL</sub>	0.02	4.5	-	-	0.1	-	0.1	-	0.1	V
Low Level Output Voltage TTL Loads			4	4.5	-	-	0.26	-	0.33	-	0.4	V
Input Leakage Current	I <sub>I</sub>	V <sub>CC</sub> and GND	0	5.5	-	-	±0.1	-	±1	-	±1	µA
Quiescent Device Current	I <sub>CC</sub>	V <sub>CC</sub> or GND	0	5.5	-	-	8	-	80	-	160	µA
Additional Quiescent Device Current Per Input Pin: 1 Unit Load	ΔI <sub>CC</sub> (Note)	V <sub>CC</sub> -2.1	-	4.5 to 5.5	-	100	360	-	450	-	490	µA

NOTE: For dual-supply systems theoretical worst case (V<sub>I</sub> = 2.4V, V<sub>CC</sub> = 5.5V) specification is 1.8mA.

## HCT Input Loading Table

INPUT	UNIT LOADS
Enable	0.7
Data Inputs	0.35

NOTE: Unit Load is ΔI<sub>CC</sub> limit specified in DC Electrical Table, e.g., 360µA max at 25°C.

## Switching Specifications Input t<sub>r</sub>, t<sub>f</sub> = 6ns

PARAMETER	SYMBOL	TEST CONDITIONS	V <sub>CC</sub> (V)	25°C			-40°C TO 85°C		-55°C TO 125°C		UNITS
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
<b>HC TYPES</b>											
Propagation Delay (Figure 1) An to Output	t <sub>PLH</sub> , t <sub>PHL</sub>	C <sub>L</sub> = 50pF	2	-	-	170	-	210	-	255	ns
			4.5	-	-	34	-	42	-	51	ns
		C <sub>L</sub> = 15pF	5	-	14	-	-	-	-	-	ns
		C <sub>L</sub> = 50pF	6	-	-	29	-	36	-	43	ns
Bn to Output	t <sub>PLH</sub> , t <sub>PHL</sub>	C <sub>L</sub> = 50pF	2	-	-	170	-	210	-	255	ns
			4.5	-	-	34	-	42	-	51	ns
		C <sub>L</sub> = 15pF	5	-	14	-	-	-	-	-	ns
		C <sub>L</sub> = 50pF	6	-	-	29	-	36	-	43	ns

**Switching Specifications** Input  $t_r, t_f = 6\text{ns}$  (Continued)

PARAMETER	SYMBOL	TEST CONDITIONS	$V_{CC}$ (V)	25°C			-40°C TO 85°C		-55°C TO 125°C		UNITS
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
$\bar{E}$ to Output	$t_{PLH}, t_{PHL}$	$C_L = 50\text{pF}$	2	-	-	120	-	150	-	180	ns
			4.5	-	-	24	-	30	-	36	ns
		$C_L = 15\text{pF}$	5	-	9	-	-	-	-	-	ns
		$C_L = 50\text{pF}$	6	-	-	20	-	26	-	30	ns
Output Transition Time (Figure 1)	$t_{TLH}, t_{THL}$	$C_L = 50\text{pF}$	2	-	-	75	-	95	-	110	ns
			4.5	-	-	15	-	19	-	22	ns
			6	-	-	13	-	16	-	19	ns
Input Capacitance	$C_{IN}$	$C_L = 50\text{pF}$	-	-	-	10	-	10	-	10	pF
Power Dissipation Capacitance (Notes 4, 5)	$C_{PD}$	$C_L = 15\text{pF}$	5	-	22	-	-	-	-	-	pF
<b>HCT TYPES</b>											
Propagation Delay (Figure 1)	$t_{PLH}, t_{PHL}$	$C_L = 50\text{pF}$	4.5	-	-	34	-	42	-	51	ns
		$C_L = 15\text{pF}$	5	-	14	-	-	-	-	-	ns
Bn to Output	$t_{PLH}, t_{PHL}$	$C_L = 50\text{pF}$	4.5	-	-	34	-	42	-	51	ns
		$C_L = 15\text{pF}$	5	-	14	-	-	-	-	-	ns
$\bar{E}$ to Output	$t_{PLH}, t_{PHL}$	$C_L = 50\text{pF}$	4.5	-	-	24	-	30	-	36	ns
		$C_L = 15\text{pF}$	5	-	9	-	-	-	-	-	ns
Output Transition Time (Figure 1)	$t_{TLH}, t_{THL}$	$C_L = 50\text{pF}$	4.5	-	-	15	-	19	-	22	ns
Input Capacitance	$C_{IN}$	$C_L = 50\text{pF}$	-	-	-	10	-	10	-	10	pF
Power Dissipation Capacitance (Notes 4, 5)	$C_{PD}$	$C_L = 15\text{pF}$	5	-	22	-	-	-	-	-	pF

## NOTES:

4.  $C_{PD}$  is used to determine the dynamic power consumption, per gate.  
 5.  $P_D = V_{CC}^2 f_i (C_{PD} + C_L)$  where  $f_i$  = Input Frequency,  $C_L$  = Output Load Capacitance,  $V_{CC}$  = Supply Voltage.

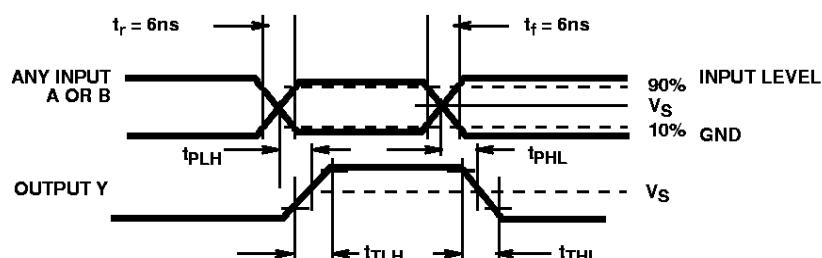
**Test Circuit and Waveform**

FIGURE 1. PROPAGATION DELAY AND TRANSITION TIMES